

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICELIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)ATTY. DOCKET NO.
MI22-1803SERIAL NO.
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Micron Technology, Inc.FILING DATE
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UnknownU.S. PTO
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U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
hy	AA	5,735,985	4/98	Ghosh et al.	156	89	
	AB	5,658,575	8/97	Ribier et al.	424	401	
	AC	6,110,401	8/00	Lee et al.	264	134	
	AD	5,597,613	1/97	Galameau et al.	427	162	
	AE	6,190,929 B1	2/01	Wang et al.	438	20	
hy	AF	6,225,143 B1	5/01	Rao et al.	438	106	
	AG						
	AH						

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AI						
	AJ						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

hy	AK	"Information About HS II RTV High Strength Moldmaking Silicone Rubber Product Line" Down Corning; 1992
	AL	"Large scale nanolithography using nanoimprint lithography"; Babak Heidari, Ivan Maximov, Eva-Lena Sarwe, and Lars Montelius; J.Vac.Sci. Technol. B17(6), Nov/Dec 1999; 1999 American Vacuum Society; pp. 2961-2964
	AM	Website: http://www.dow.com/cyclotene/prods/prod1.htm : Cyclotene: Photosensitive Resins; 5/14/2001
	AN	Website: http://www.dow.com/cyclotene/apps/app11.htm : Cyclotene: Bumping/Redistribution/Wafer Level Packaging (WLP); 5/14/2001
hy	AO	Website: http://www.dow.com/cyclotene/apps/app13.htm : Cyclotene: Multilayer Interconnects; 5/14/01

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U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.
M122-1803

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LIST OF ART CITED BY APPLICANT
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	AJ							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
ky	AK		Website: http://www.dow.com/cyclotene/over.htm : Cyclotene: BCB Properties; 5/14/01
ky	AL		Website: http://www.dow.com/cyclotene/over/tg.htm : Tg vs Cure; 5/14/01
ay	AM		"New polymer materials for nanoimprinting"; H. Schulz et al.; J. Vac. Sci. Technol. B18(4) July/Aug 2000; pp. 1861-1865
	AN		

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